
Silicon Tungsten Calorimetry

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- Design Consideration
- Silicon Detector Design
- Electrons and Noise
- Mechanical Design
- Timing resolution
- Plans and lab activity
- Si-W Mechanical Design

Si-W work – personnel and responsibilities

M. Breidenbach, D. Freytag,
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SLAC

Electronics,
Mechanical Design,
Simulation

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Si Detectors,
Mechanical Design,
Simulation

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Electronics

Primary ECAL Design Requirements

- Excellent separation of γ 's from charged particles
Efficiency > 95% for energy flow
- Good reconstruction of π^\pm , detection of neutral hadrons
- Reasonable EM energy resolution ($< 15\%/\sqrt{E}$)
- Reconstruct τ 's and measure polarization (separate π , ρ , a_1 , e's)
- Reconstruct Bhabhas and deconvolve luminosity spectra
Position resolution $\sim 100\mu\text{m}$, bias $\sim 25\mu\text{m}$ in endcap

Secondary ECAL Design Requirements

- Excellent electron identification in jets (tag and b/c quarks)
- Partial reconstruction of b/c hadrons in jets
- Good γ impact resolution for long lived SUSY neutrals
 $\sim 1 \text{ cm}$
- Good background immunity
 - Bunchlet identification
 - High granularity

SiW Design Consideration

- Transverse shower size scales with Molière radius (9mm in pure W, 16mm in pure Pb)

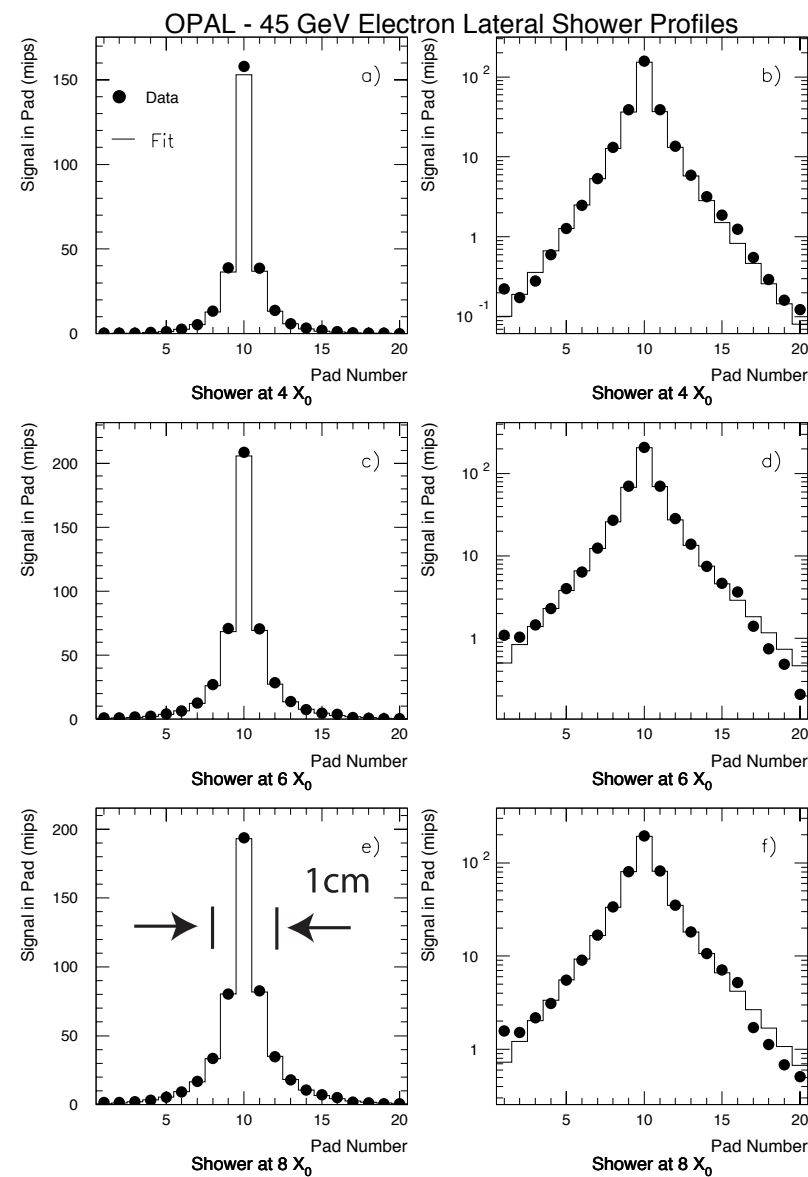
⇒ *Minimize gaps between layers of absorber*

⇒ *Use a high purity W alloy*

- Sample between 1/2 and 2/3 of X_0 (1.75mm to 2.5mm of W)

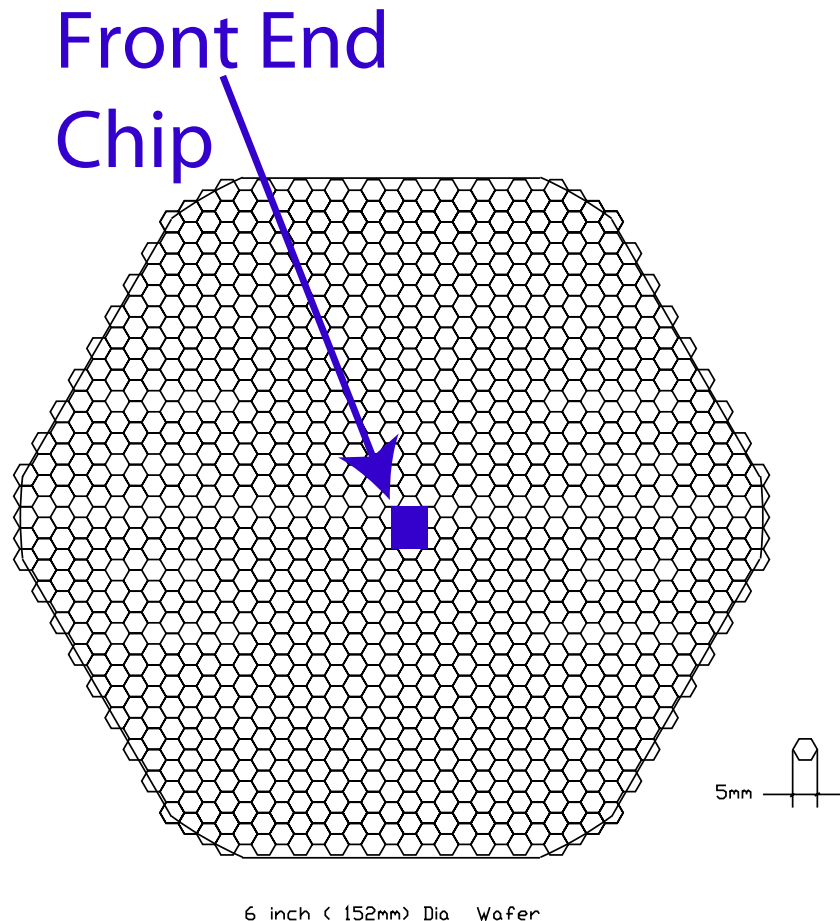
- Allow for detector segmentation at a fraction of the Molière radius

⇒ *Use $\sim 5\text{mm}$ pads*



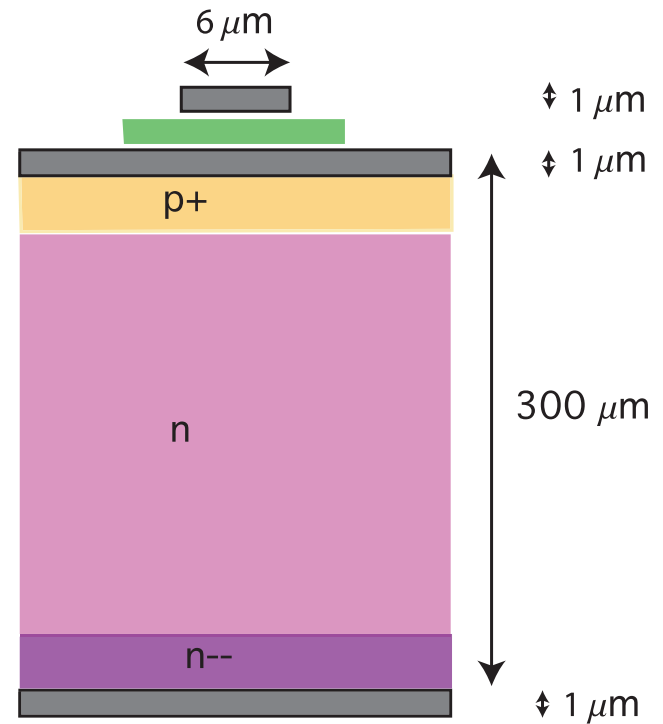
Silicon Concept

- Readout each wafer with a single chip
- Bump bond chip to wafer
- To first order cost independent of pixels /wafer
- Hexagonal shape makes optimal use of Si wafer
- Channel count limited by power consumption and area of front end chip
- May want different pad layout in forward region



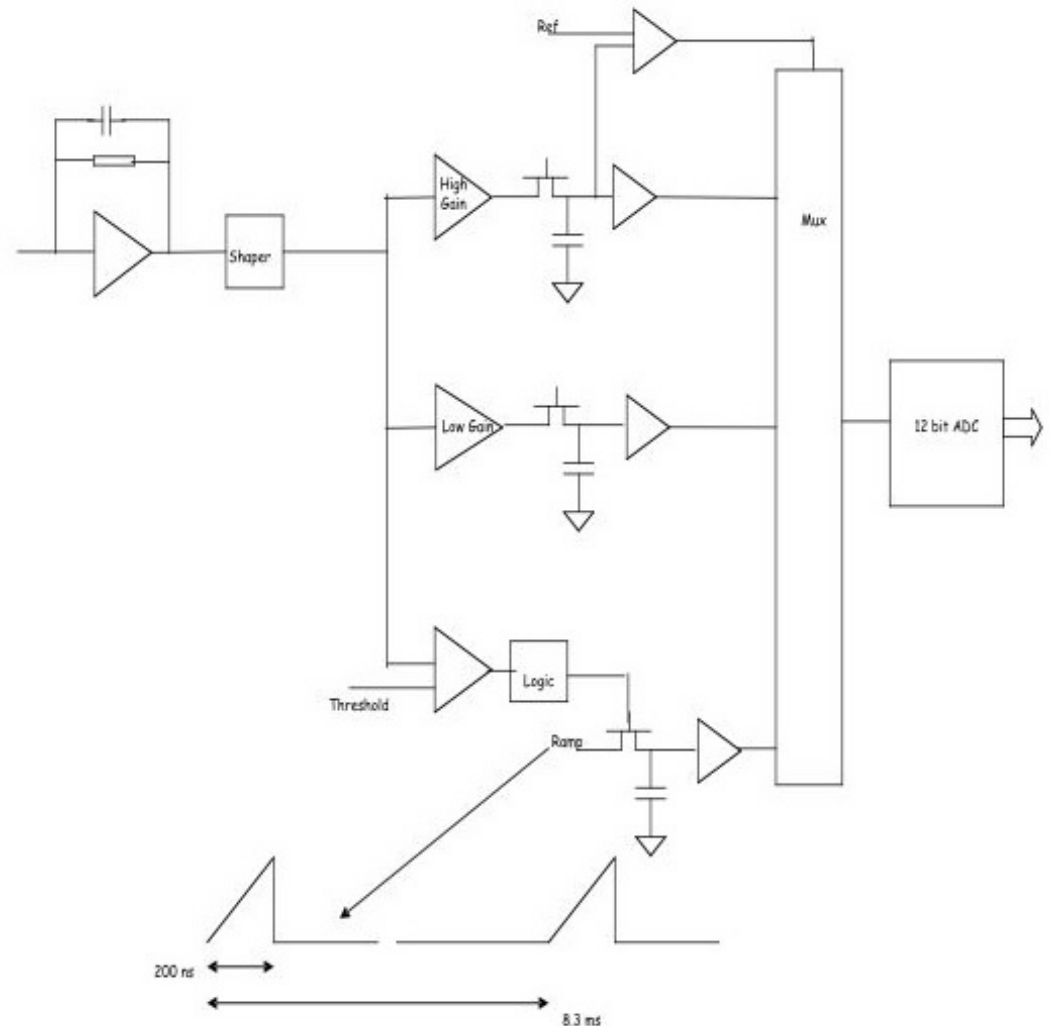
Silicon Design Details

- DC coupled detectors
- Two metal layers
- Keep Si design as simple as possible to reduce cost
- Cross talk looks small with current electronics design



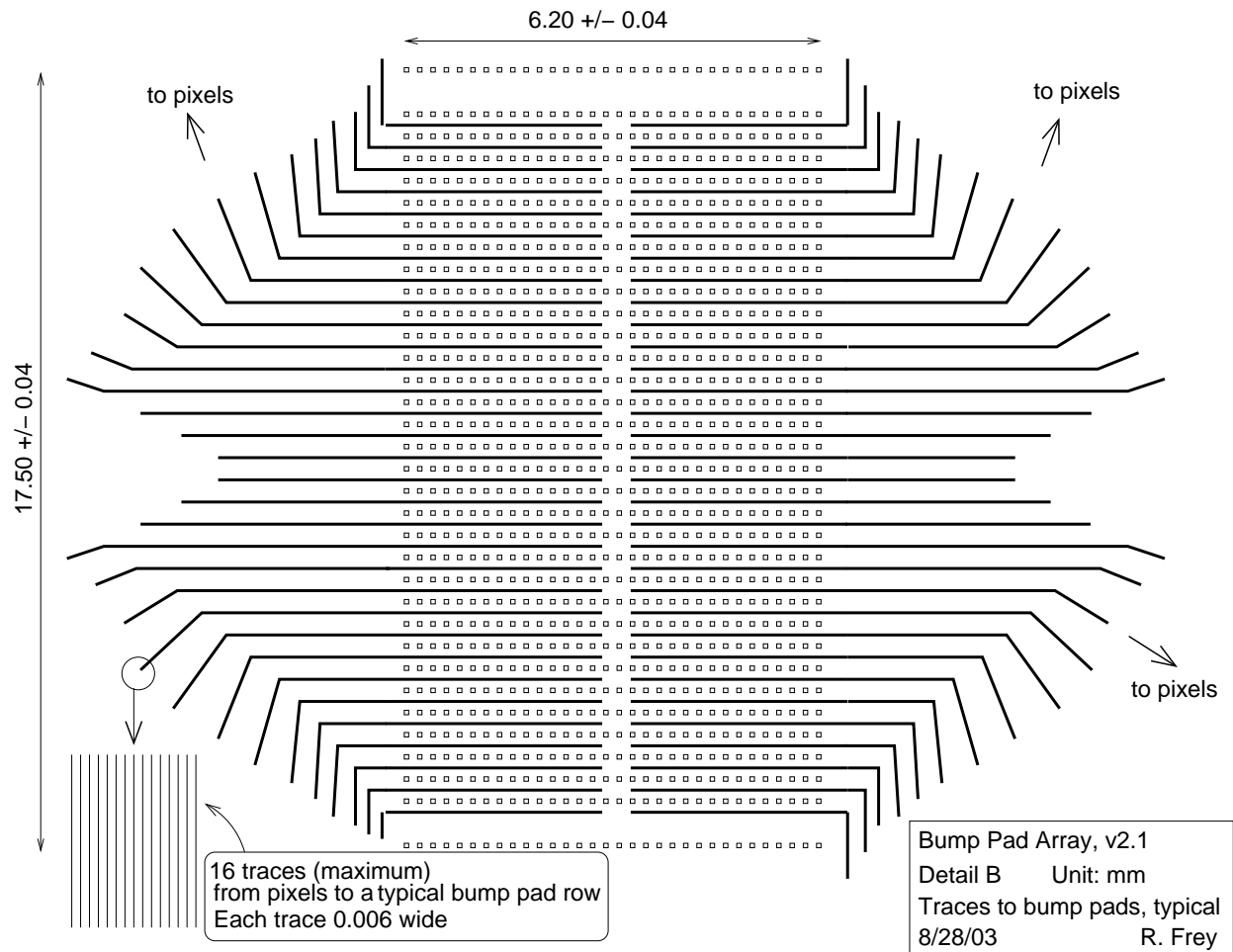
Electronics Design

- Chip area driven by feedback capacitor on charge integrator and 3V supply.
Need 2000 MIP (8 pC) dynamic range for 500 GeV electrons.
⇒ 10pF feedback capacitor needed
- New design samples integrated ($\tau = 200\text{ns}$) signal after $1\mu\text{s}$ for each bunch train
Lowers cross talk, little gain variation with bunch-let number
- Timing at the 10ns level should be possible
- Current in input transistor pulsed
duty cycle $< 10^{-3}$ 0.1mW/ch
- Currently estimating chip area and power needed for digital section



Si Prototypes

- Design completed
Provisional grid spacing for bump-bonding



Si Prototype properties – leakage current and noise

- Radiation damage to detectors is probably dominated by neutrons, $\sim 10 \times 10^{10}/\text{cm}^2$

$\Rightarrow < 10\text{nA} / \text{pixel}$ leakage current

- Expect typical leakage current at start of life $< 1\text{nA}/\text{pixel}$
- Noise from leakage current at end-of-life for $1\mu\text{s}$ sampling time (can be adjusted) and DC coupling scheme is < 350 electrons

-
- Largest source of electronics noise will be front-end input transistor, noise scales as

$$\frac{C_{in}}{\sqrt{\tau}I^{1/4}} \propto \frac{C_{in}}{\sqrt{\tau}\text{power}^{1/4}}$$

- Present design has noise:

$$\sim 20 - 30e/\text{pf}$$

For most channels the value of C_{input} is dominated by stray capacitance of the trace connecting the pixels to the electronics:

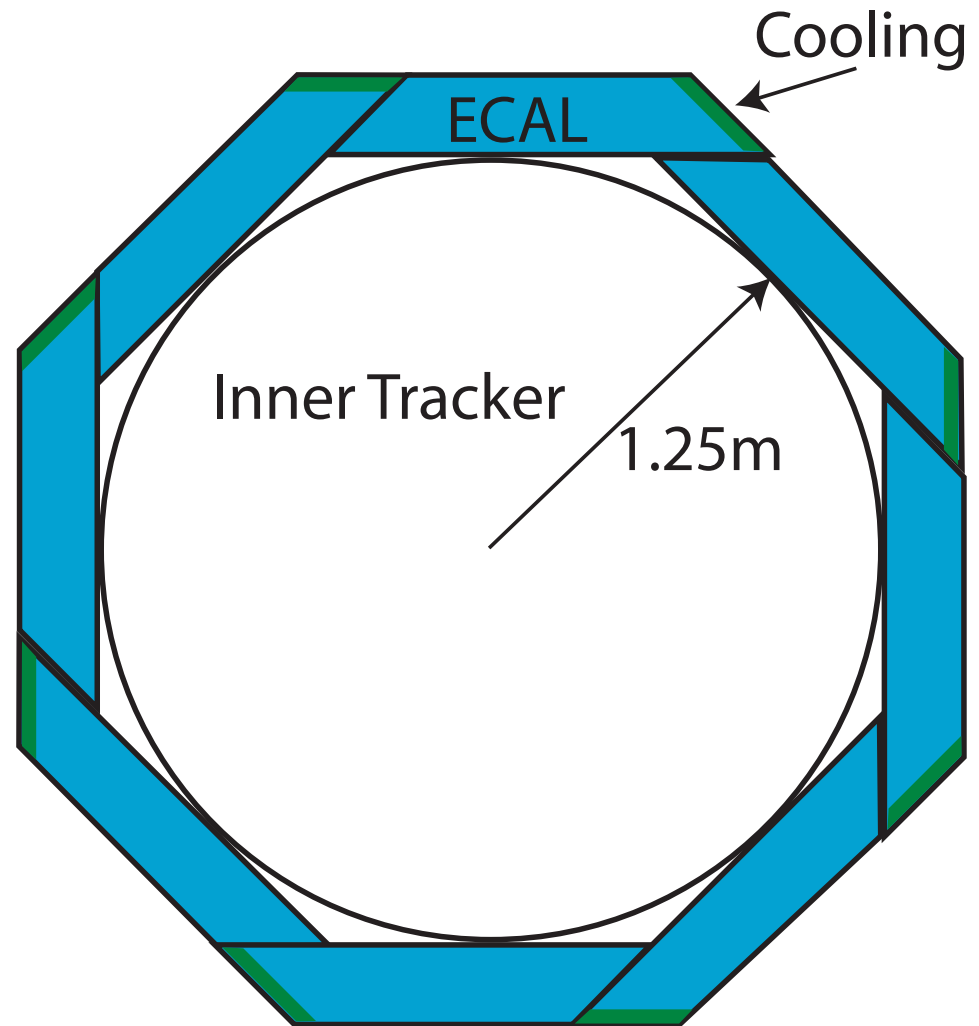
$$C_{input} \sim 5.7\text{pF}(\text{pixel}) + 12\text{pF}(\text{trace}) + 10\text{pF}(\text{amp}) \sim 30\text{pF}$$

$$\longrightarrow \sim 1000 \text{ electrons noise (c.f. 24,000 from MIP)}$$

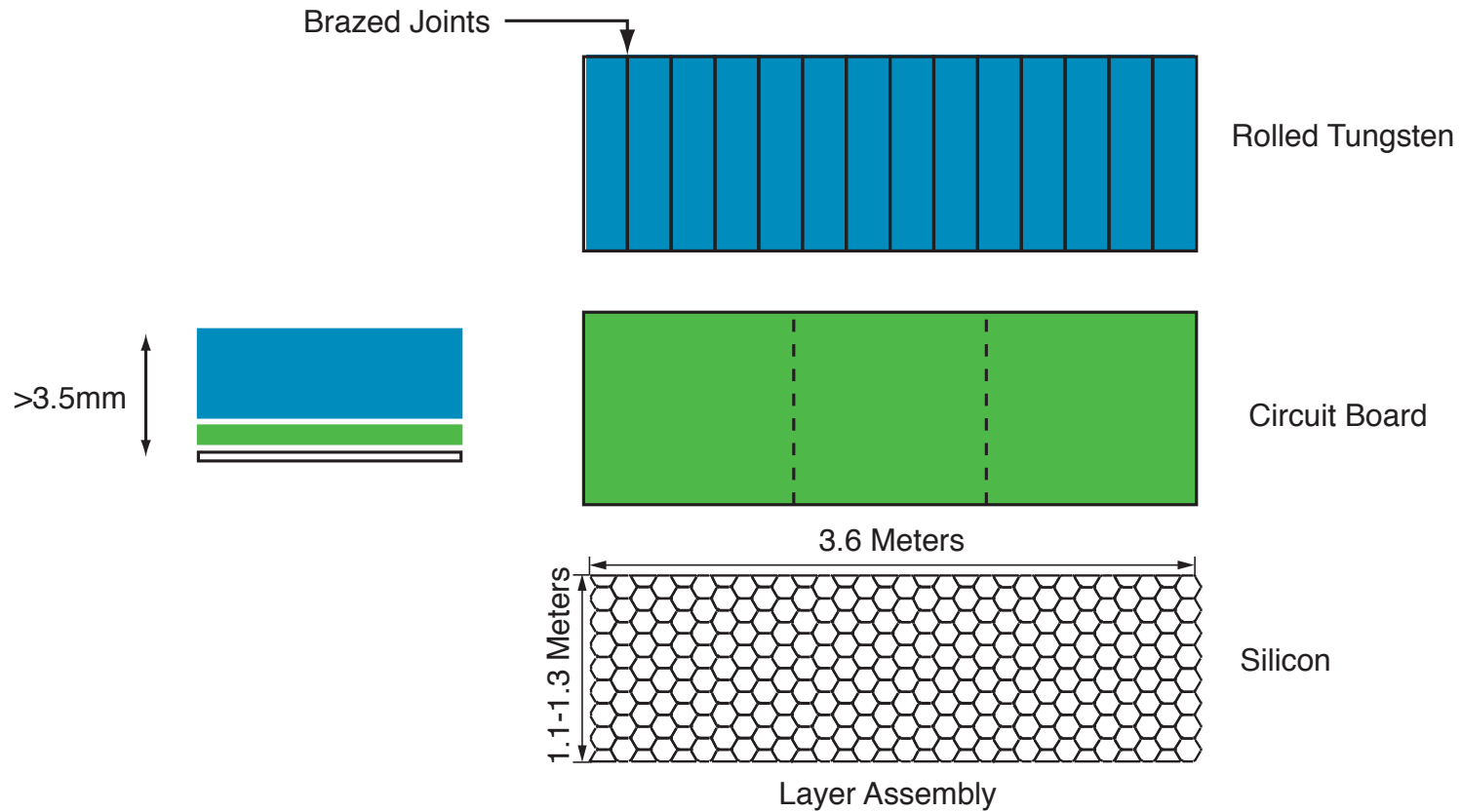
- Analog power consumption will probably be driven by timing requirements (under investigation)

Fitting it all together

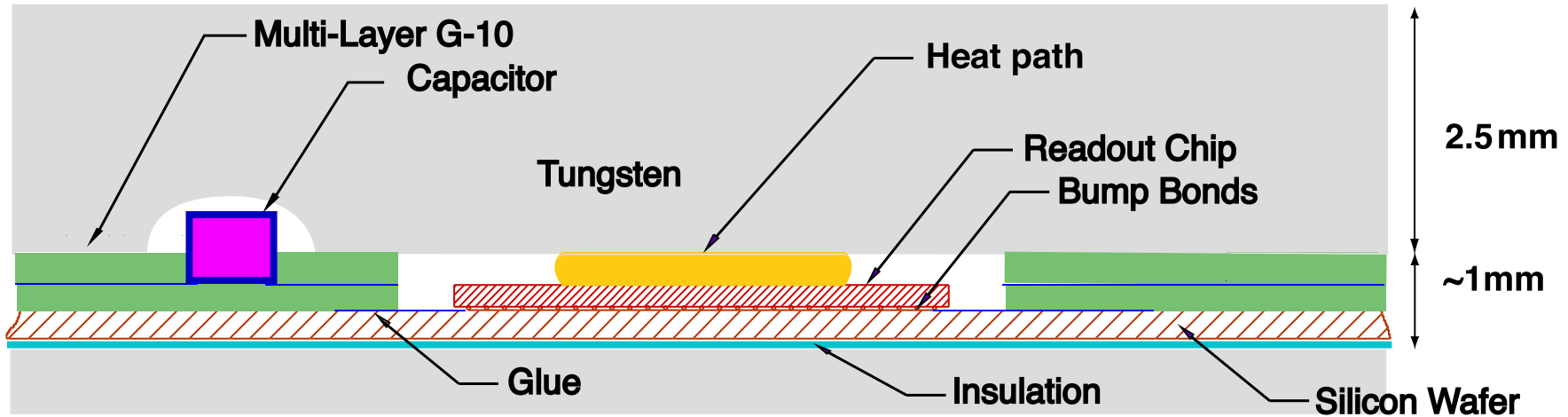
- Cartoon of possible barrel calorimeter configuration
- Assume heat flows along tungsten and/or copper heat sink to cooling water (green)
- Longest path for heat flow $< 1.4\text{m}$



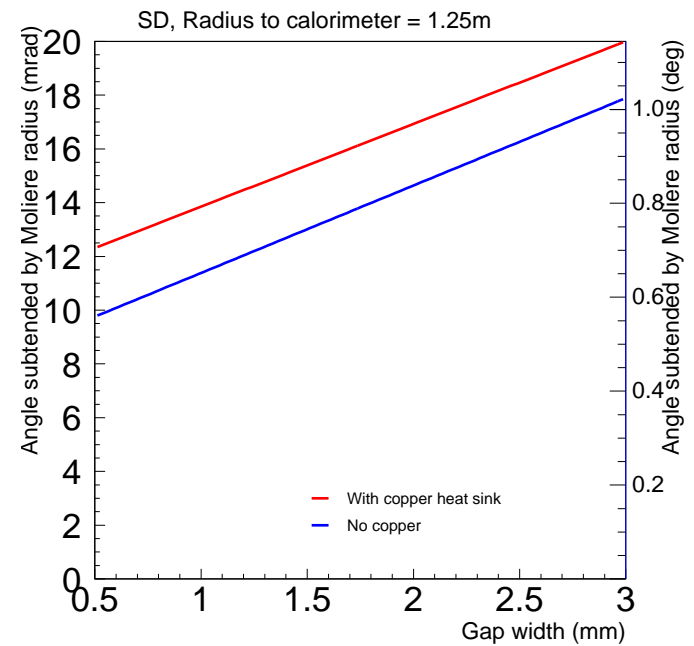
Layout of Individual calorimeter layers:



Critical parameter: minimum space between tungsten layers.



Config.	Radiation length	Molière Radius
100% W	3.5mm	9mm
92.5% W	3.9mm	10mm
+1mm gap	5.5mm	14mm
+1mmCu	6.4mm	17mm



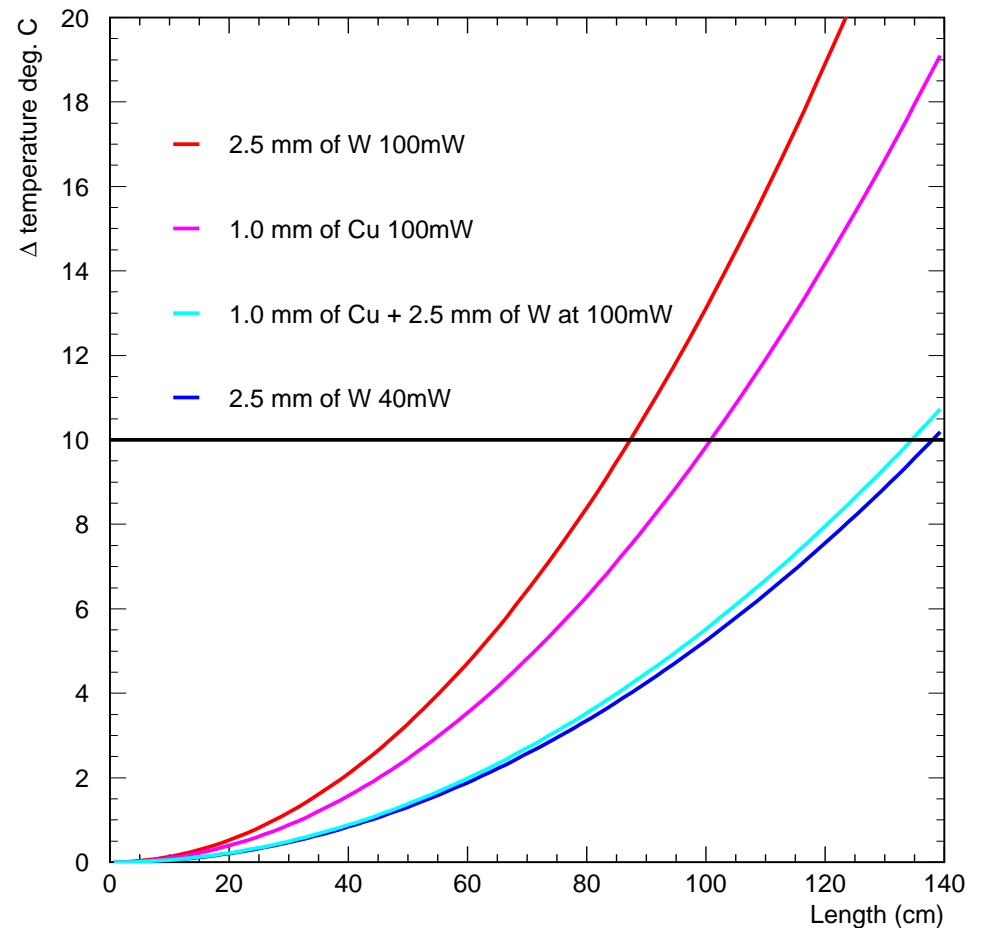
Heat flow

Back of the envelope calculation of change in temperature:

- Thermal Conductivity of W alloy $120\text{W}/(\text{K}\cdot\text{m})$
- Thermal Conductivity of Cu $400\text{W}/(\text{K}\cdot\text{m})$

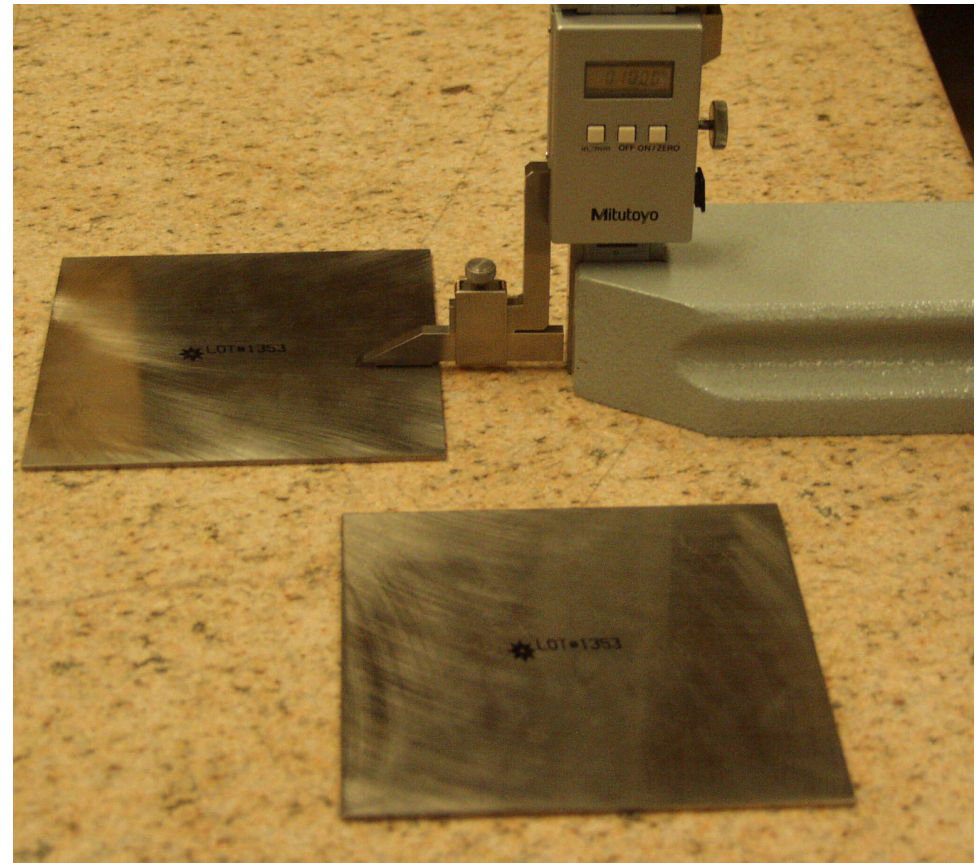
Need to reduce heat to below $100\text{mW}/\text{wafer}$.

Physical model test in progress



Prototype Tungsten Pieces

- OPAL tungsten ground to size (almost more expensive than tungsten itself!)
- Prototype rolled pieces (92.5% W) look fine (some grinding still needed)
- Quality better than OPAL
- 1 m long pieces possible



Summary of Granularity – *Most important figure of merit*

- With 92.5% W and 1 mm gap we can have a Molière radius of

~ 14 mm

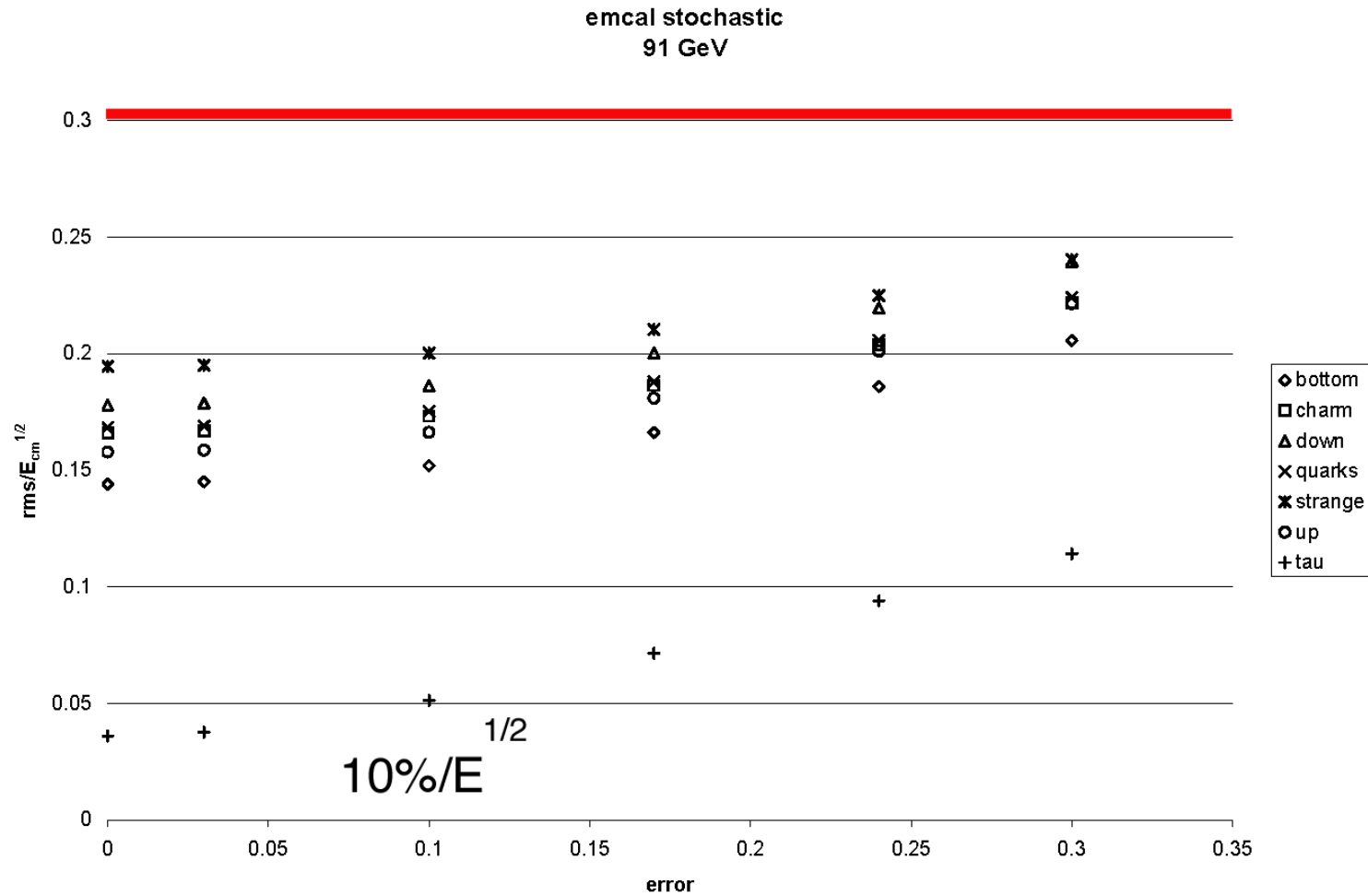
which has an angular size of **11 mrad** at 1.25 m

⇒ provided we can keep the power down to **40 mW** wafer

- *This will be challenging, but may be possible*

What about energy resolution ⇒

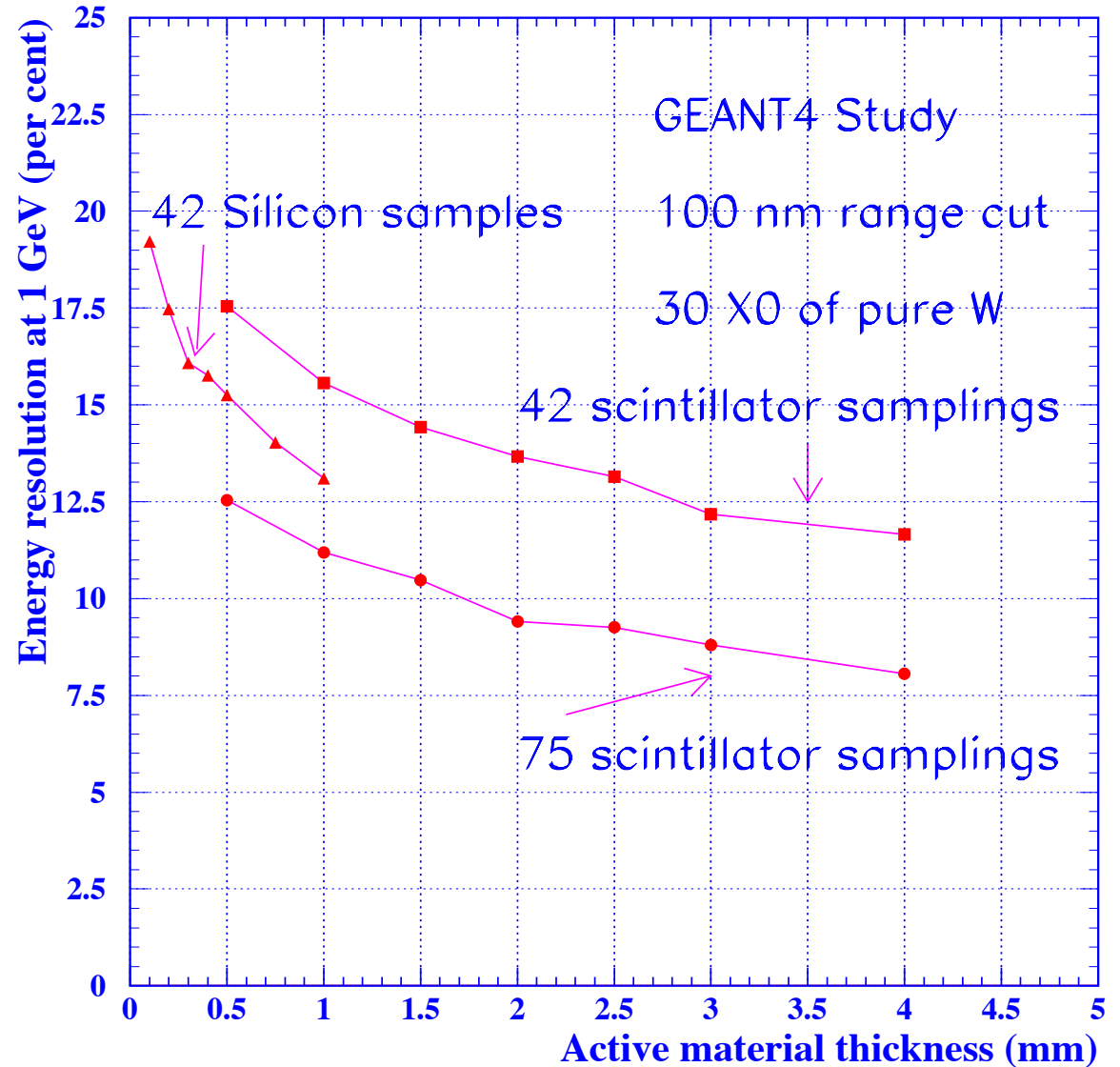
Jet energy resolution will suffer if we give up too much sampling
(Graham Wilson's plot):



Assumes $\sigma_{p_t}/p_t^2 = 5 \times 10^{-5}$, HCAL res $50\%/\sqrt{E} \oplus 4\%$

Geant 4 simulation of energy resolution from Graham Wilson

- 1 GeV photons
- 0.1 μm range cuts
- 42 and 75 layers of W
- Si apparently benefits from subMIP energy deposits – can we see this in a real detector?

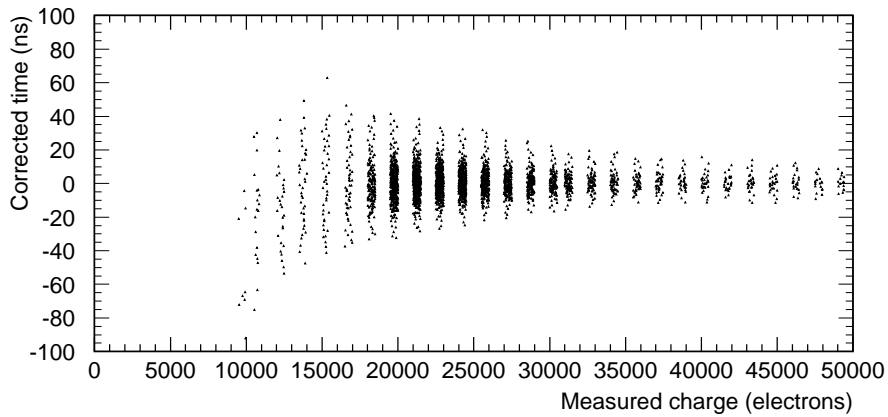
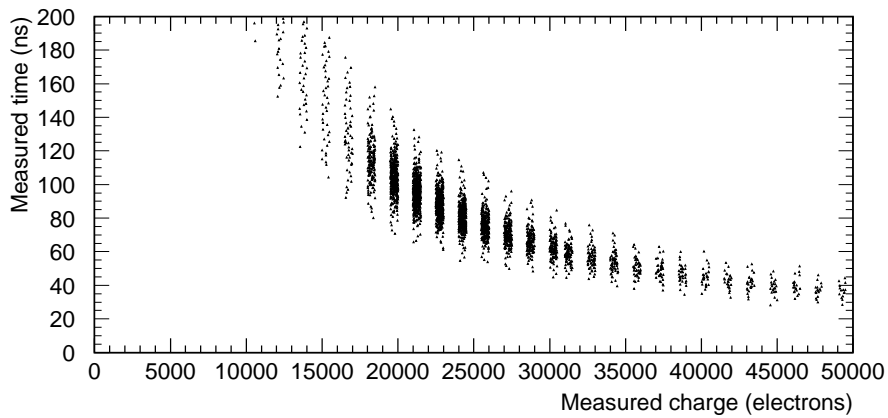


Toy Monte Carlo Studies of Timing Resolution for 30 Samples

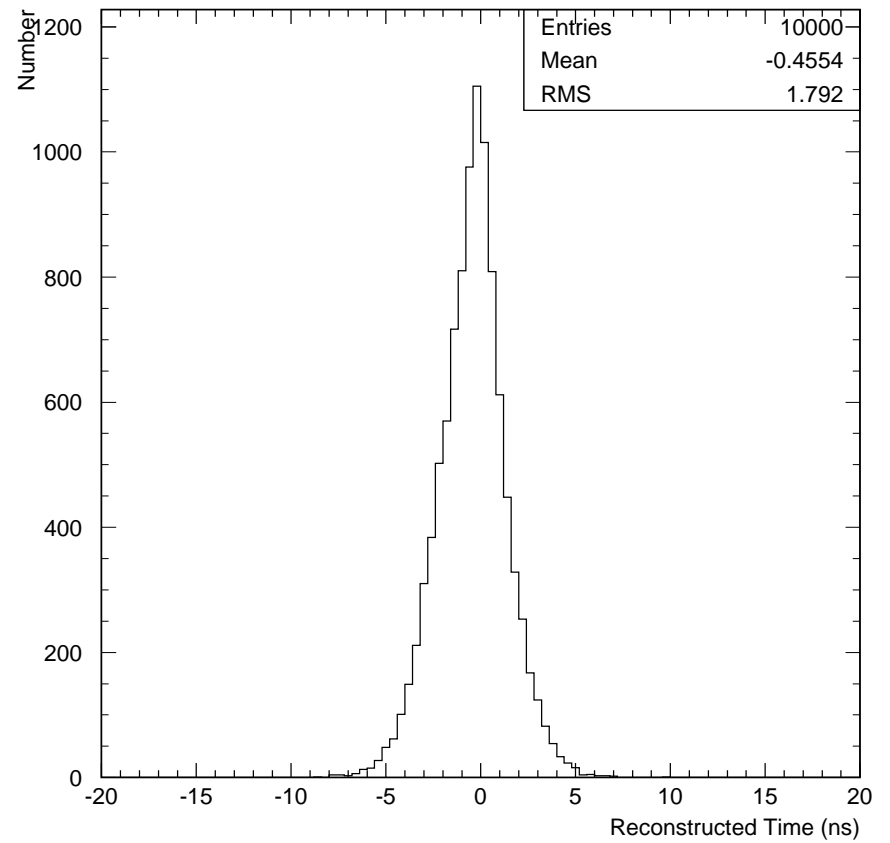
Assumptions – wild guesses – (waiting for real electronics model):

- Timing circuit and charge amplifier have the same integration time of 200 ns.
- Input FET has $g_m = 2\text{mS}$
- Excess noise is equal to FET noise
- Includes reasonable distribution of capacitances from second metal layers
- Threshold is set at 8000 electrons (Typical noise ~ 1000 electrons)
- 5% jitter channel-to-channel, 1% common mode jitter in thresholds
- Charge granularity of $0.061 \cdot 1\text{MIP}$
- Channel-to-channel leakage current variations perfectly corrected

Sample Timing Results

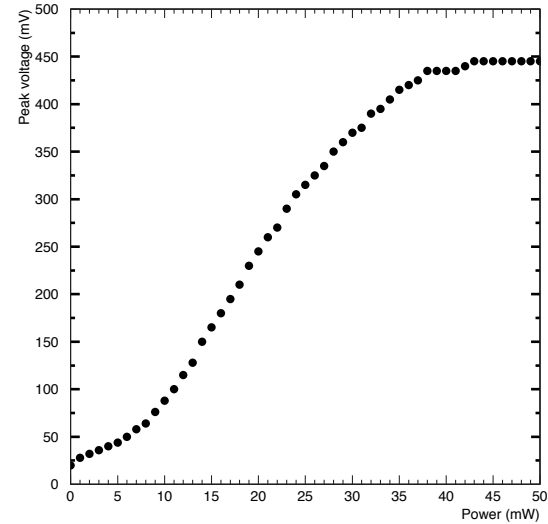
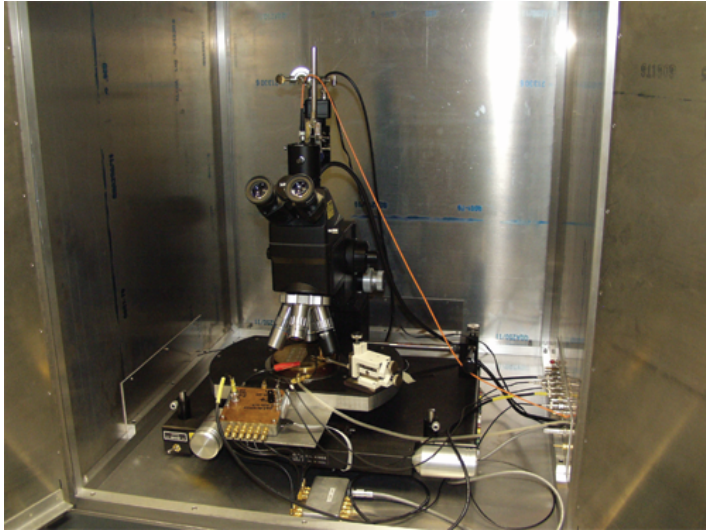


Time versus charge for mips

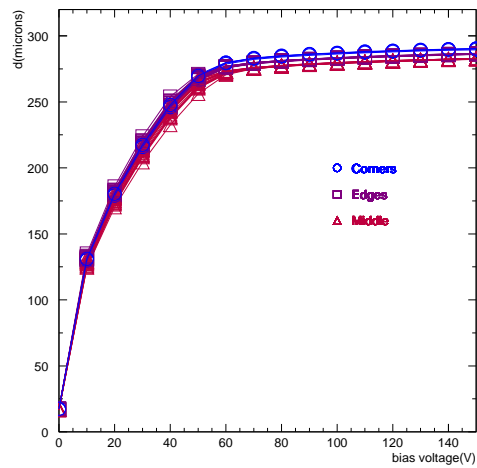


30 Sample average time

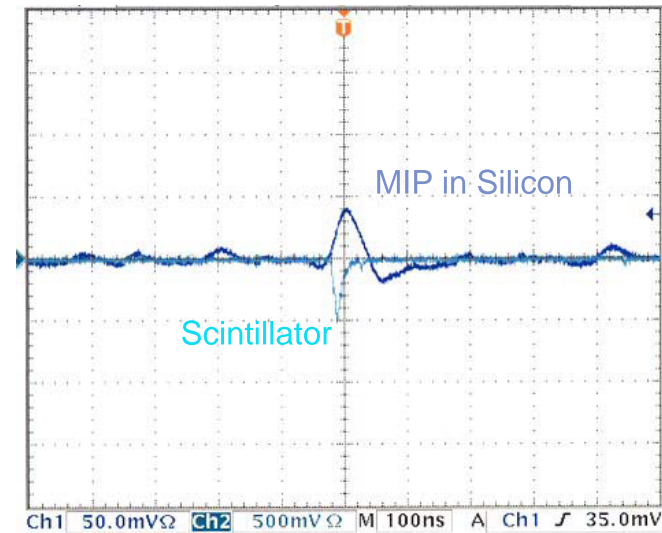
Practice with 6x6 1cm² cell detectors: Probe station



Depletion depth from CV curve



MIP with scintillator



Si-W status

- Design of first silicon detectors complete
⇒ Prototypes will arrive in early '04
- Electronics rough draft complete
⇒ Expect to be ready for submission in early '04
- Mechanical conceptual design started
⇒ ~ 1 mm gap between layers without a copper heat sink may be possible
⇒ Gap size depends crucially on power consumption

Si-W Near Term Plans

- Produce prototype electronics – early next year
- Test bump bonding electronics to detectors in '04
- Ready for Test Beam in '05
- Confirm thermal model and explore best coupling method of chips to absorber
- Simulation job list:
 - Optimize sampling for energy resolution
 - Compare GEANT 4 /EGS and data on Eres versus silicon thickness
 - Optimize pixel layout
 - Would more granularity help?
 - How sensitive is energy flow to Molière radius?